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REDLINE VERSION

colour inside

Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection – Glossary – Part 4-4: Piezoelectric materials – ~~Materials~~ Single crystal wafers for surface acoustic wave (SAW) devices

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Part 4-4: Piezoelectric materials – ~~Materials~~ Single crystal wafers for surface acoustic wave (SAW) devices

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Technical specifications are subject to review within three years of publication to decide whether they can be transformed into International Standards.

IEC TS 61944-4-4, which is a technical specification, has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

This third edition of IEC 61994-4-4 cancels and replaces the second edition published in 2010. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) the new terms and definitions given in IEC 62276:2016 have been taken into account;

b) the general title has been changed according to the change in the title of TC 49 in 2009.

c) the part title has been changed according to the title of IEC 62276:2016.

The text of this technical specification is based on the following documents:

Enquiry draft	Report on voting
49/1283/DTS	49/1287/RVC

Full information on the voting for the approval of this technical specification can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

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PIEZOELECTRIC, DIELECTRIC AND ELECTROSTATIC DEVICES AND ASSOCIATED MATERIALS FOR FREQUENCY CONTROL, SELECTION AND DETECTION – GLOSSARY –

Part 4-4: Piezoelectric materials – ~~Materials~~ Single crystal wafers for surface acoustic wave (SAW) devices

1 Scope

This part of IEC 61994 ~~specifies~~ gives the terms and definition for single crystal wafers ~~applied~~ for surface acoustic wave (SAW) devices representing the state of the art~~, which are intended for use in the standards and documents of IEC technical committee 49~~.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

~~ISO 4287, *Geometrical Product Specifications (GPS) – Surface texture: Profile method – Terms, definitions and surface texture parameters*~~

There are no normative references in this document.

IEC TS 61994-4-4

Edition 3.0 2018-11

TECHNICAL SPECIFICATION

Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection – Glossary – Part 4-4: Piezoelectric materials – Single crystal wafers for surface acoustic wave (SAW) devices



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Part 4-4: Piezoelectric materials – Single crystal wafers for surface acoustic wave (SAW) devices

1 Scope

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